TrenchMOSTM transistor Standard level FET

BUK7608-55

GENERAL DESCRIPTION

N-channel enhancement mode standard level field-effect power transistor in a plastic envelope suitable for surface mounting. Using 'trench' technology the device features very low on-state resistance and has integral zener diodes giving ESD protection up to 2kV. It is intended for use in automotive and general purpose switching applications.

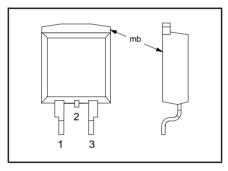
QUICK REFERENCE DATA

SYMBOL	PARAMETER	MAX.	UNIT
V _{DS} I _D Ptot T _j R _{DS(ON)}	Drain-source voltage Drain current (DC) Total power dissipation Junction temperature Drain-source on-state resistance V _{GS} = 10 V	55 75 187 175 8	> A ⊗ ℃ Ω

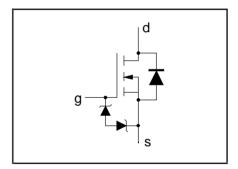
PINNING - SOT404

PIN	DESCRIPTION		
1	gate		
2	drain		
3	source		
mb	drain		

PIN CONFIGURATION



SYMBOL



LIMITING VALUES

Limiting values in accordance with the Absolute Maximum System (IEC 134)

SYMBOL	PARAMETER	CONDITIONS	MIN.	MAX.	UNIT
V _{DS}	Drain-source voltage	-	-	55	V
V_{DGR}	Drain-gate voltage	$R_{GS} = 20 \text{ k}\Omega$	-	55	V
±V _{GS}	Gate-source voltage	- "	-	16	V
I _D	Drain current (DC)	$T_{mb} = 25 ^{\circ}C$	-	75	Α
l _D	Drain current (DC)	T _{mb} = 100 °C	-	65	Α
I _{DM}	Drain current (pulse peak value)	T _{mb} = 25 °C	-	240	Α
P _{tot}	Total power dissipation	$T_{mb}^{mb} = 25 ^{\circ}C$	-	187	W
T_{stg}, T_{i}	Storage & operating temperature	- ""	- 55	175	°C

ESD LIMITING VALUE

SYMBOL	PARAMETER	CONDITIONS	MIN.	MAX.	UNIT
V _C	Electrostatic discharge capacitor voltage, all pins	Human body model (100 pF, 1.5 kΩ)	-	2	kV

THERMAL RESISTANCES

SYMBOL	PARAMETER	CONDITIONS	TYP.	MAX.	UNIT
R _{th j-mb}	Thermal resistance junction to mounting base	-	-	0.8	K/W
$R_{\text{th j-a}}$	Thermal resistance junction to ambient	Minimum footprint, FR4 board	50	-	K/W

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STATIC CHARACTERISTICS

T_i= 25°C unless otherwise specified

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
$V_{(BR)DSS}$	Drain-source breakdown	$V_{GS} = 0 \text{ V}; I_D = 0.25 \text{ mA};$	55	-	-	V
	voltage	$T_i = -55^{\circ}C$	50	-	-	V
$V_{GS(TO)}$	Gate threshold voltage	$V_{DS} = V_{GS}$; $I_D = 1 \text{ mA}$	2	3.0	4.0	V
33(13)			1	-	-	V
		T _j = 175°C T _i = -55°C	-	-	4.4	V
I _{DSS}	Zero gate voltage drain current	$V_{DS} = 55 \text{ V}; V_{GS} = 0 \text{ V};$	-	0.05	10	μΑ
		T _i = 175°C	-	-	500	μA
I _{GSS}	Gate source leakage current	$V_{GS} = \pm 10 \text{ V}; V_{DS} = 0 \text{ V}$	-	0.02	1	μA
		$T_{i} = 175^{\circ}C$	-	-	20	μA
$\pm V_{(BR)GSS}$	Gate-source breakdown	$I_G = \pm 1 \text{ mA};$	16	-	-	·V
(=: 1)	voltage					
R _{DS(ON)}	Drain-source on-state	$V_{GS} = 10 \text{ V}; I_D = 25 \text{ A}$	-	6.5	8	mΩ
Bo(on)	resistance	$T_j = 175^{\circ}C$	-	-	17	mΩ

DYNAMIC CHARACTERISTICS

 $T_{mb} = 25^{\circ}C$ unless otherwise specified

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
g _{fs}	Forward transconductance	$V_{DS} = 25 \text{ V}; I_{D} = 25 \text{ A}$	10	45	-	S
C _{iss} C _{oss} C _{rss}	Input capacitance Output capacitance Feedback capacitance	$V_{GS} = 0 \text{ V}; V_{DS} = 25 \text{ V}; f = 1 \text{ MHz}$		3600 830 320	4500 1000 440	pF pF pF
$egin{array}{c} t_{d\ on} \ t_r \ t_{d\ off} \ t_f \end{array}$	Turn-on delay time Turn-on rise time Turn-off delay time Turn-off fall time	$V_{DD}=30~V;~I_{D}=25~A;$ $V_{GS}=10~V;~R_{G}=10~\Omega$ Resistive load	- - -	27 70 100 50	40 105 140 70	ns ns ns ns
L _d	Internal drain inductance Internal source inductance	Measured from upper edge of drain tab to centre of die Measured from source lead soldering point to source bond pad	-	2.5 7.5	-	nH nH

REVERSE DIODE LIMITING VALUES AND CHARACTERISTICS

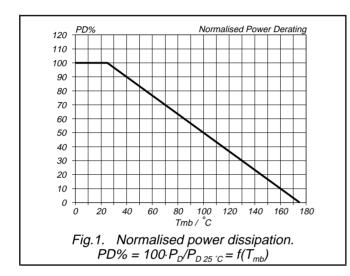
 $T_i = 25$ °C unless otherwise specified

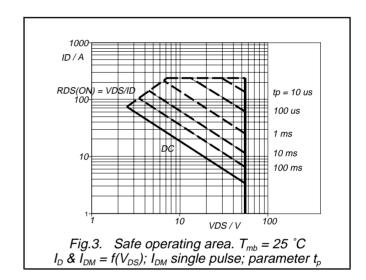
SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
I _{DR}	Continuous reverse drain current		-	-	75	Α
I _{DRM}	Pulsed reverse drain current		-	-	240	Α
V_{SD}	Diode forward voltage	$I_F = 25 \text{ A}; V_{GS} = 0 \text{ V}$ $I_F = 75 \text{ A}; V_{GS} = 0 \text{ V}$	-	0.85	1.2	V
-	-	$I_F = 75 \text{ A}; V_{GS} = 0 \text{ V}$	-	1.0	-	V
t _{rr}	Reverse recovery time	$I_F = 75 \text{ A}; -dI_F/dt = 100 \text{ A/}\mu\text{s};$	-	65	-	ns
\dot{Q}_{rr}	Reverse recovery charge	$V_{GS} = -10 \text{ V}; V_{R} = 30 \text{ V}$	-	0.18	-	μC

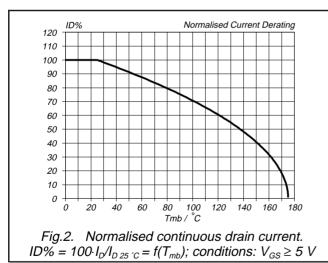
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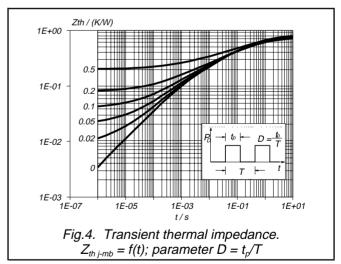
AVALANCHE LIMITING VALUE

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
W _{DSS}		$I_D = 75 \text{ A}; V_{DD} \le 25 \text{ V};$ $V_{GS} = 10 \text{ V}; R_{GS} = 50 \Omega; T_{mb} = 25 \text{ °C}$	-	ı	500	mJ









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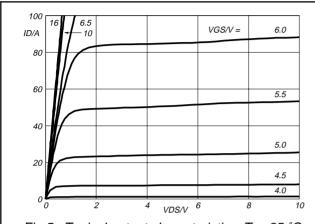


Fig.5. Typical output characteristics, $T_j = 25$ °C. $I_D = f(V_{DS})$; parameter V_{GS}

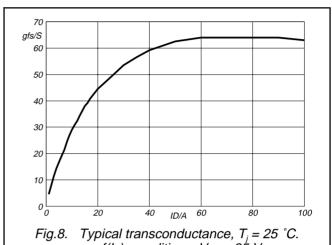
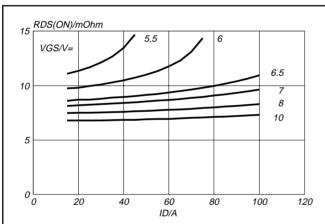


Fig.8. Typical transconductance, $T_j = 25$ °C. $g_{fs} = f(I_D)$; conditions: $V_{DS} = 25$ V



Typical on-state resistance, $T_j = 25$ °C. $R_{DS(ON)} = f(I_D)$; parameter V_{GS}

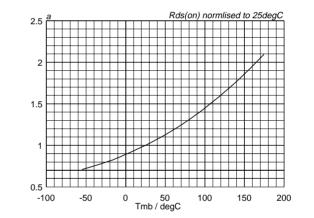
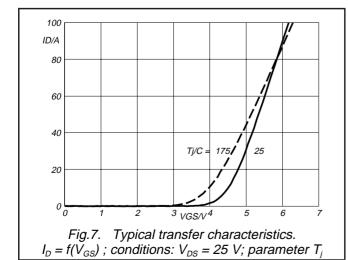
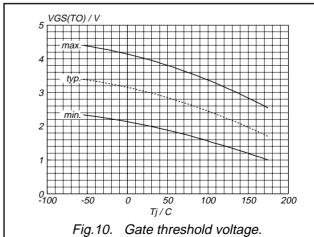


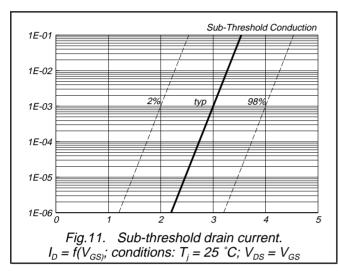
Fig.9. Normalised drain-source on-state resistance. $a = R_{DS(ON)}/R_{DS(ON)25 \, ^{\circ}C} = f(T_i); I_D = 25 \, A; V_{GS} = 5 \, V$

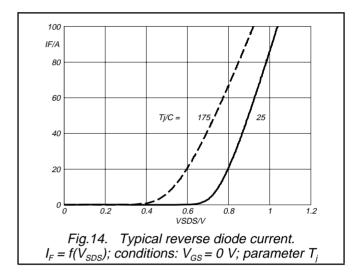


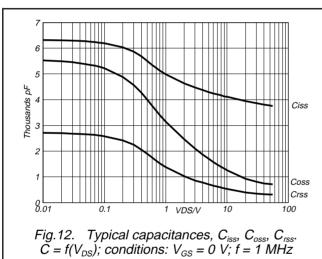


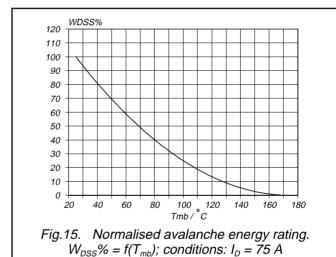
 $V_{GS(TO)} = f(T_i)$; conditions: $I_D = 1$ mA; $V_{DS} = V_{GS}$

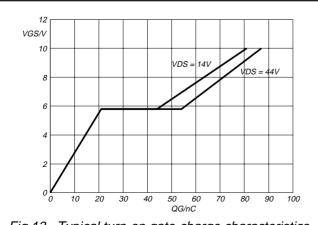
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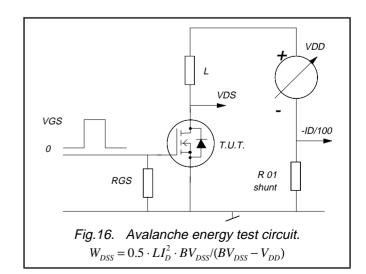
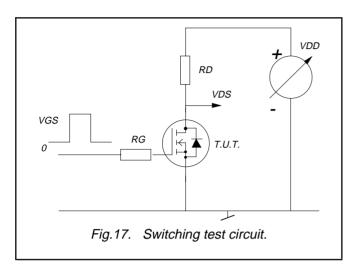


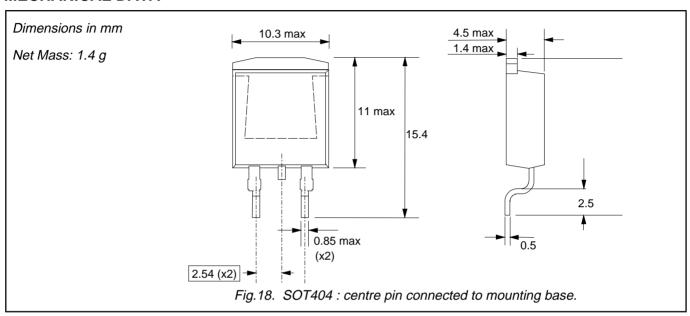
Fig.13. Typical turn-on gate-charge characteristics. $V_{GS} = f(Q_G)$; conditions: $I_D = 50 \text{ A}$; parameter V_{DS}

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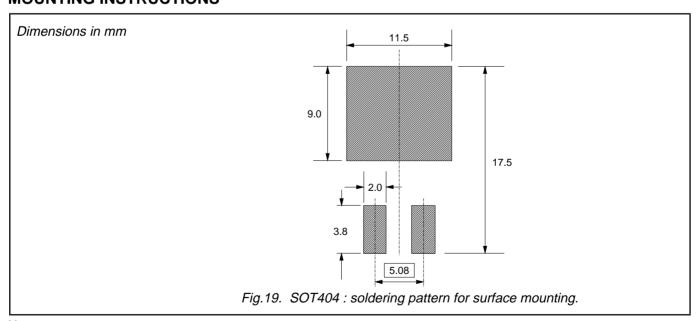


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MECHANICAL DATA



MOUNTING INSTRUCTIONS



Notes

- 1. Observe the general handling precautions for electrostatic-discharge sensitive devices (ESDs) to prevent damage to MOS gate oxide.
- 2. Epoxy meets UL94 V0 at 1/8".

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DEFINITIONS

Data sheet status					
Objective specification	This data sheet contains target or goal specifications for product development.				
Preliminary specification	This data sheet contains preliminary data; supplementary data may be published later.				
Product specification	This data sheet contains final product specifications.				
Limiting values					

Limiting values are given in accordance with the Absolute Maximum Rating System (IEC 134). Stress above one or more of the limiting values may cause permanent damage to the device. These are stress ratings only and operation of the device at these or at any other conditions above those given in the Characteristics sections of this specification is not implied. Exposure to limiting values for extended periods may affect device reliability.

Application information

Where application information is given, it is advisory and does not form part of the specification.

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